

Semiconductor

STOCK LIST

No.	Maker	Item	Model	Vintage	Configuration	Remark
1	JEOL	FE-EPMA	JXA-8530F	2017	<ul style="list-style-type: none"> •JXA-8530F(5ch) Plus •EPMA Data processor •Phase analysis program •Irregular sample analysis program •Trace element analysis program •Phase map Maker •Liquid nitrogen trap •Chiller •Active Vibration removal stand 	
2	JEOL	SEM	JSM-6510LV	2014	<ul style="list-style-type: none"> •JSM-6510LV •EDS AMETEK EDAX Octane Pro •Operation Keyboard •Motor Controlled Stage(2 Axis) 	
3	JEOL	SEM	JSM-6360LV	2004	<ul style="list-style-type: none"> •JSM-6360LV SEM main unit •EDAX G-XM2 CDU/SUTW •61090(MS) 2-axis motor stage(Max specimen size 150 mm, 80x40mm) •47414 PC unit(2 USB port, PC card slot) •34470 backscatter electron detector •47512 CRT monitor •65020(PRD2) device for photography •65040(CSI2) device for scan Image photography •65150(OKB) operation keyboard •49020 chiller •LGSHL solvent holder 	
4	Keyence	3D Surface Measurement Microscope	VE-9800S	2006	with 3D/Motorized Stage EDAX G-XM2 CDU/SUTW	

5	Olympus	Semiconductor wafer inspection microscope	2006	<ul style="list-style-type: none"> •Brightfield/Darkfield illuminator+Fiber Adapter(BX-RLA2+U-LGAD) •Motorized Nosepiece 6-Position RMS Threads(ob: 1.25x 2.5x 10x 20x 50x 100xBD)(U-D6REM) •Levo Controller/Hand switch(U-REMCB/U-HSTR) •Light Guide •Transmission Light unit •Imaging lens(Camera adapter)/touble port(U-TLU+U-TV0.5XC) •Light Reduction Filter/Color Temperature Conversion Filter •Color camera(Including the manual measurement function) •Stage and stage driving controller •Color video printers and ACC •Auto focus unit and PC 	
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Price is being negotiated (not secured/매입 검토중)

No.	Maker	Item	Model	Vintage	Configuration	Remark
1	Hitachi	SEM	S-3700N	2017	SEM, Large sample chamber (maximum 300mm diameter), 5-axis MD, Camera navigation, Secondary electron/Reflective electron, Low-vacuum secondary electron detector ESED-II, EDX HORIBA EMAX Evolution X Max50 EX470	
2	Hitachi	SEM	SU3500	2016	SEM, Secondary electron detector, Reflection electron detector, Low-vacuum secondary electron detector, EDX (American Tech Octane Plus), MC1000 ion sputtering, Etc.	
3	Hitachi	SEM	S-3400N	2011	SEM, Type 1, Secondary electron detector, Reflection electron detector, Maximum sample size 200mm×35mm thickness, Turbo-molecular pump	
4	Shimadzu	Microfocus X-Ray CT System	inspe X io SMX225CT FPD HR	2016	FPD-16, 8CL-H, Data processing system, Image analysis S/W, Subworkstations, Etc.	
5	Mitutoyo	CNC Measuring System	QV-A808P8L-D	2021	Color camera, 4 turret, objective QV-HR2.5/5/10x, measuring range 800x800x150mm, minimum display 0.1μm, External dimensions 1475Wx1860Dx1578Hmm, mass approximately 2600kg	
6	Nikon	Fluorescent Microscope	ECLIPSE Ni-U	2015	Fluorescent Microscope Eclipse Ni-U 3-Lens Set Fluorescent NiU-T-RFLM-4	
7	Leica	Stereo Microscope	M80	2017	M80, Object lens Plan 1.0x, LED ring light lighting, Binocular tilt lens barrel 45 degrees, Eyepiece 10x (x2), Ergo wedge, Photo tube, Digital camera MC170HD, C-mount, Flex Arm, 15.6" Monitor	
8	Hitachi	SEM	SU1510	2011	•SU1510 Main unit Φ153mm at the maximum sample size, 2-axis motor drive stage Low/high vacuum one-touch conversion Turbo Molecular Pump (TMP) is standard 4 segment solid state type BSE detector secondary electron (SE) detector •EDAX Qualitative Quantitative Mapping System Windows PC No liquid Nitrogen Silicon Drift Detectors	

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